

11/26/03

Sheet 1 of 1

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 024808-00015	SERIAL NO. 101726, 252 Unknown
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		APPLICANT Yoh TAKANO	
		FILING DATE November 26, 2003	GROUP 2827 Unknown

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO PART.
TNT	AG	02-154388	June 13, 1990	Japan			X
	AH						
	AI						
	AJ						
	AK						
	AL						

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

TNT	AM	Junichi Yamada, Tohru Miwa, Hiroki Koike, and Hideo Toyoshima, "A Self-Reference Read Scheme for a 1T/1C FeRAM, 1998 IEEE
TNT	AN	"Ferroelectric Thin Film Memory," Seventh Section "Liability and Assessment Technology of Ferroelectric Memory," I. Switching Fatigue Characteristic, June 30, 1994
TNT	AO	Second Section, MRAM, "Now in production and coming in 2004, 256 M bit," Nikkei Electronics, February 12, 2001 (No. 789), pp. 164-171

EXAMINER:	TAN T. Nguyen	DATE CONSIDERED
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.